

|                                   |  |                         |   |             |
|-----------------------------------|--|-------------------------|---|-------------|
| <b>Notice of References Cited</b> |  | Application/Control No. | Applicant(s)/Patent Under Reexamination |             |
|                                   |  | 10/825,146              | WINARSKI ET AL.                         |             |
| Examiner                          |  | Michael Kroccheck       | Art Unit                                | Page 1 of 1 |
| 2186                              |  |                         |   |             |

**U.S. PATENT DOCUMENTS**

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Name                  | Classification |
|---|---|--|-----------------|-----------------------|----------------|
| * | A | US-5,805,932 A                                   | 09-1998         | Kawashima et al.      | 710/68         |
| * | B | US-6,084,739 A                                   | 07-2000         | Assouad, Nicolas C.   | 360/77.08      |
| * | C | US-6,185,661 B1                                  | 02-2001         | Ofek et al.           | 711/145        |
| * | D | US-6,373,800 B1                                  | 04-2002         | Takahashi, Hideki     | 369/53.15      |
| * | E | US-2002/0136214 A1                               | 09-2002         | Do et al.             | 370/392        |
| * | F | US-2003/0033316 A1                               | 02-2003         | Morgan, George J. III | 707/100        |
| * | G | US-2003/0126359 A1                               | 07-2003         | Debiez et al.         | 711/112        |
| * | H | US-2003/0126446 A1                               | 07-2003         | Debiez et al.         | 713/178        |
| * | I | US-2005/0007685 A1                               | 01-2005         | Winarski et al.       | 360/060        |
| * | J | US-6,976,623 B1                                  | 12-2005         | Mambakkam et al.      | 235/441        |
|   | K | US-  |                 |                       |                |
|   | L | US-  |                 |                       |                |
|   | M | US-  |                 |                       |                |

**FOREIGN PATENT DOCUMENTS**

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
|   | N |  |                 |         |      |                |
|   | O |  |                 |         |      |                |
|   | P |  |                 |         |      |                |
|   | Q |  |                 |         |      |                |
|   | R |  |                 |         |      |                |
|   | S |  |                 |         |      |                |
|   | T |  |                 |         |      |                |

**NON-PATENT DOCUMENTS**

|   |   |   |
|---|---|---|
| * |   | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|   | U |   |
|   | V |   |
|   | W |   |
|   | X |   |

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.